

Standard Test Methods for High-Brightness LEDs

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CNC/CIE Workshop 2012

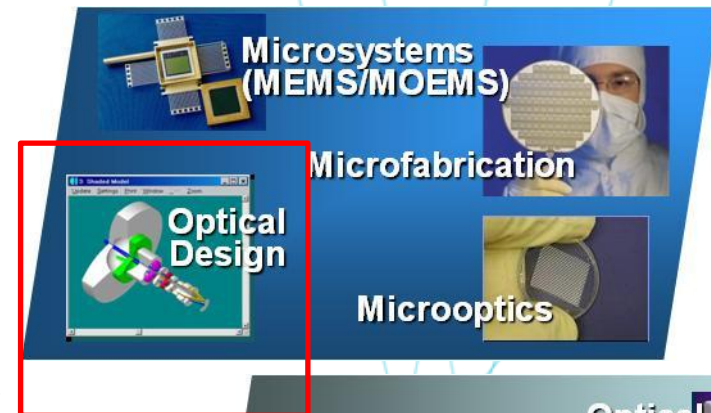
Opportunities and Challenges in Energy-Efficient Lighting

November 30th, 2012

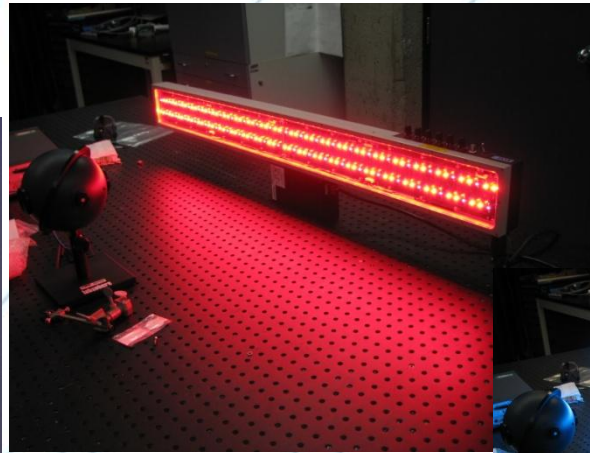
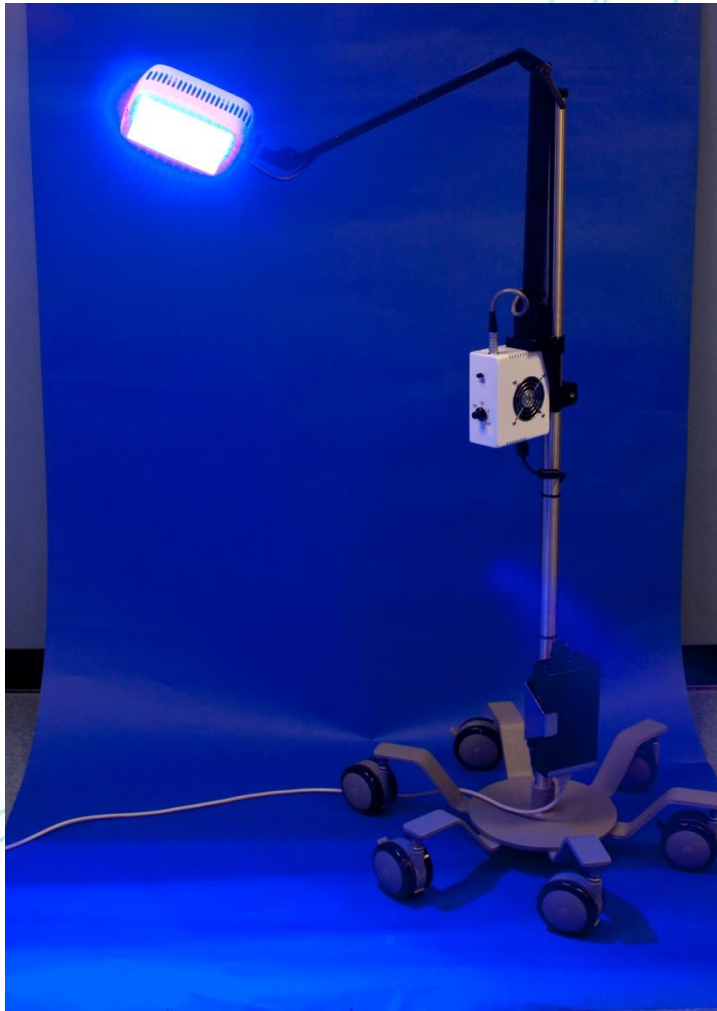
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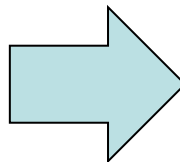
> 200 employees, 38M\$ budget , 40 technology transfers, 26 spinoffs companies, 5,000 R&D contracts, 23 agreements with the international scientific community, 107 patents granted, 100 other are pending



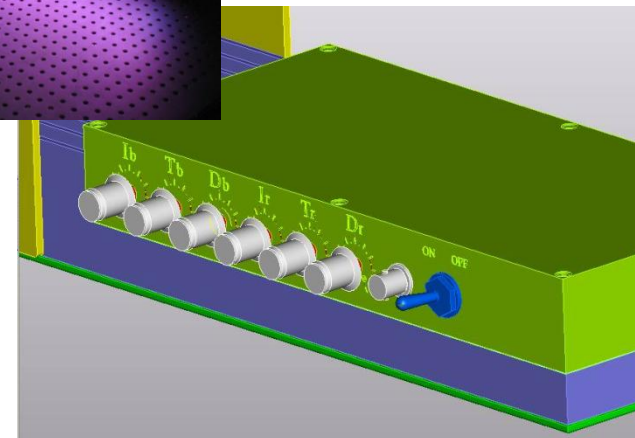
Led sources



High power
Controlled performance



LED
characterization



Characterizing LEDs: what should be tested?

In order to support the design of high quality SSL (solid state lighting) products, the engineer should know the following LED parameters:

- _ Performance characteristics

- _ Photometric quantities: luminous flux, light intensity distribution, luminance
 - _ Chromatic quantities: chromaticity, CCT, CRI, CQS, color angular/spatial uniformity
 - _ Source luminous efficacy (lm/W)
 - _ Thermal behavior: variations of photometric and chromatic quantities with temperature
 - _ Reliability and lifetime, lumen maintenance, color stability

This data is useful, for example, to ensure that a SSL product using the LED meets performance requirements

We are interested in performance measurements of high power LEDs

High power LEDs: characterization issues

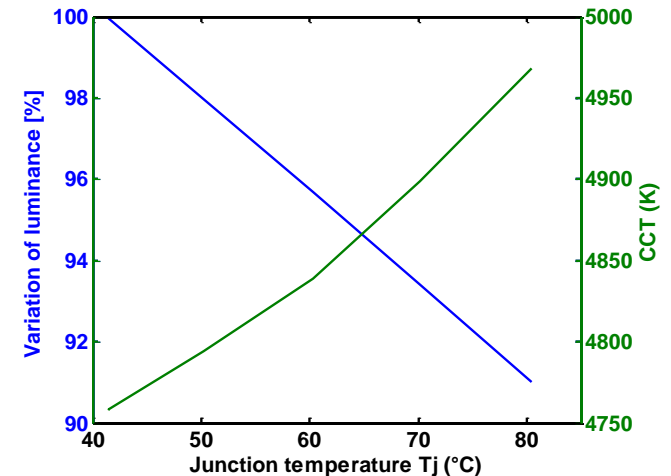
_ LEDs manufacturers typically specify devices performance at room temperature and for a typical operating current.

however

_ High power LEDs in luminaires operates at much higher temperature depending on the SSL heat sink efficiency, operating current and ambient temperature.

_ Many performance parameters vary with temperature

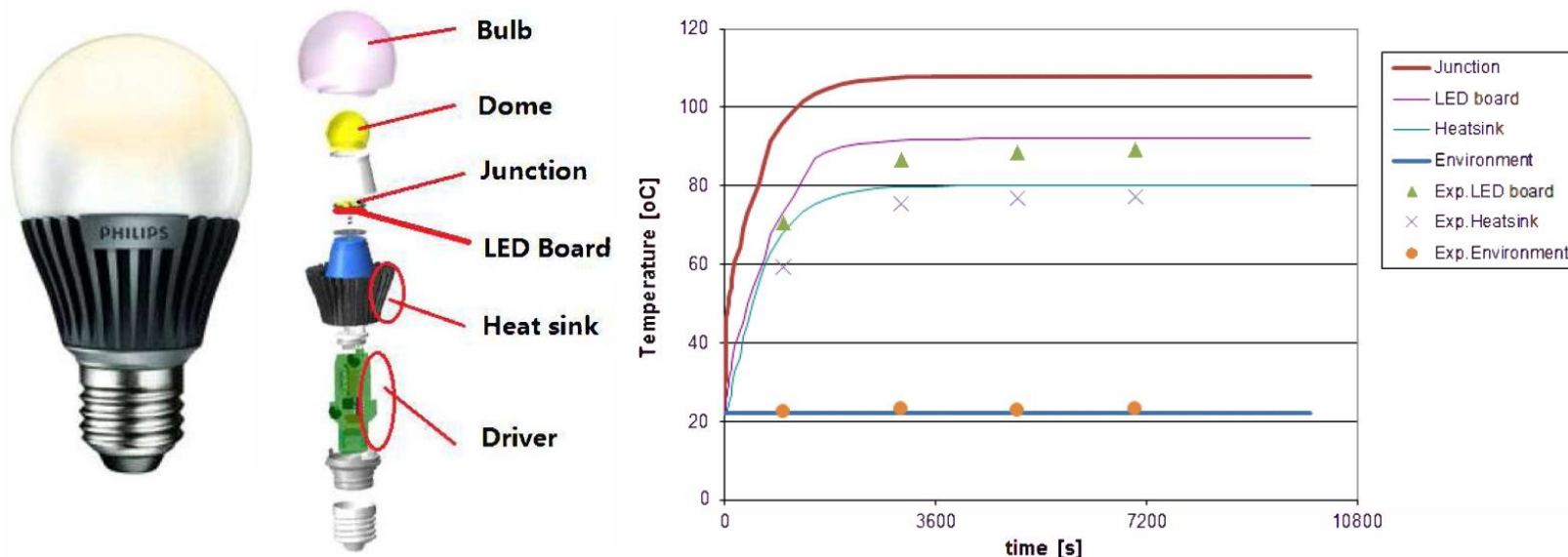
- _ Emitted spectrum
- _ Chromaticity, CCT, CRI
- _ Luminous flux and radiant flux
- _ Wall plug and luminous efficacies



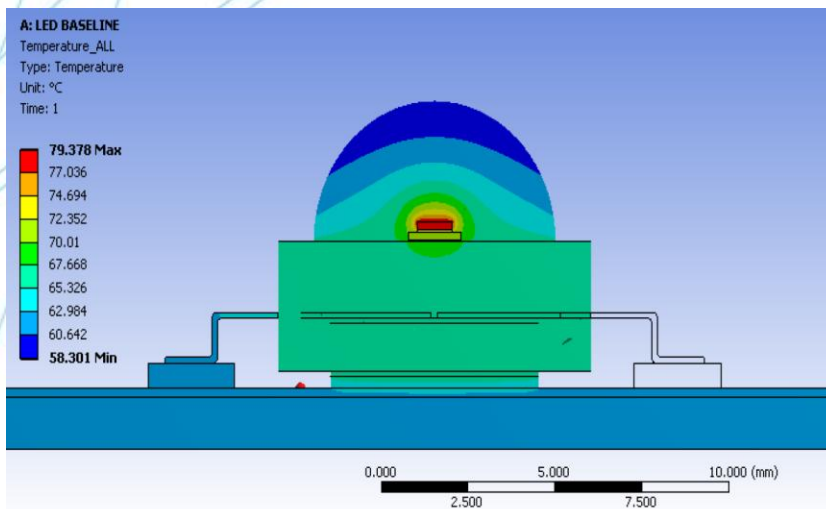
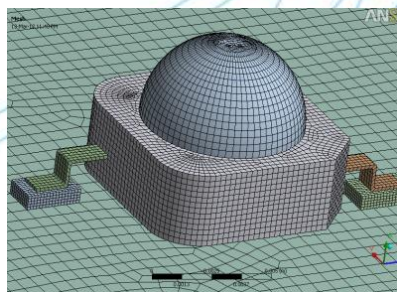
ACULed White emitter in a RGBW LED, 700mA

**Performance of LEDs extracted from datasheet
≠
Performance in of SSL products**

Examples of SSL thermal analysis



From: Dynamic thermal simulation of high brightness LEDs with unsteady driver power output, H. Ye, EuroSimE 2012



| Power (W) | 1 | 2 | 3 |
|-----------|------|-------|-------|
| Tj (°C) | 79.3 | 129.2 | 175.8 |

Tambient = 25°C
 $\delta T = 150^\circ\text{C}$ with 3W dissipated power

From: A Parametric Study of a Typical High Power LED Package to Enhance Overall Thermal Performance, A. Vipradas, 13th IEEE ITherm Conference, 2012

Standardization effort

CIE and IESNA are defining new standards for measurement of **high-power LEDs**

TC 2-63: Optical Measurement of High-Power LEDs

To develop a CIE recommendation on methods for the operation of high-power LEDs in DC and in pulse mode, **at specified junction temperatures**, for optical measurements. Chair: [Yugin Zong](#) (US)

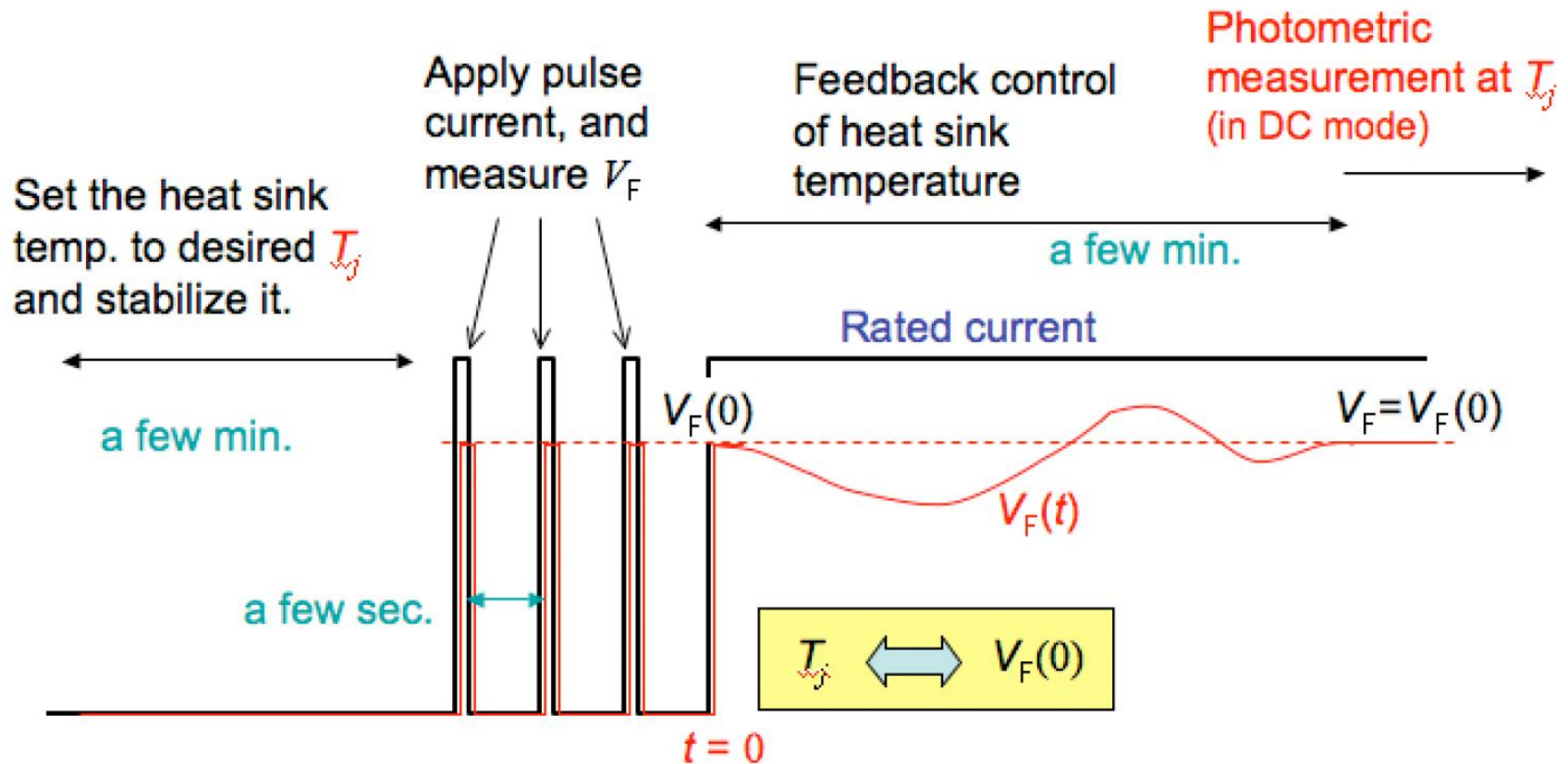
IESNA LM-85: Approved Method for Electrical and Photometric Measurement of High Power LEDs (non official description)

Address the measurements for high-power LEDs that require heat sink for their normal operation, and include white LEDs as well as single color LEDs.

- _ Measure total luminous flux, total radiant flux (optical power), electrical power, luminous efficacy, and color characteristics of high-power LEDs
- _ Measure under pulse operation as well as steady DC operation of LEDs, and **in all cases, the thermal condition of LEDs refers to their junction temperature**
- _ Does not cover measurement of ultraviolet LEDs, IR emitters, and AC-LEDs.

Setting the junction temperature T_j

— **One proposed method.** From “NEW PRACTICAL METHOD FOR MEASUREMENT OF HIGH-POWER LEDS”, Yuguang Zong and Yoshi Ohno (NIST), CIE Expert Symposium 2008 on Advances in Photometry and Colorimetry

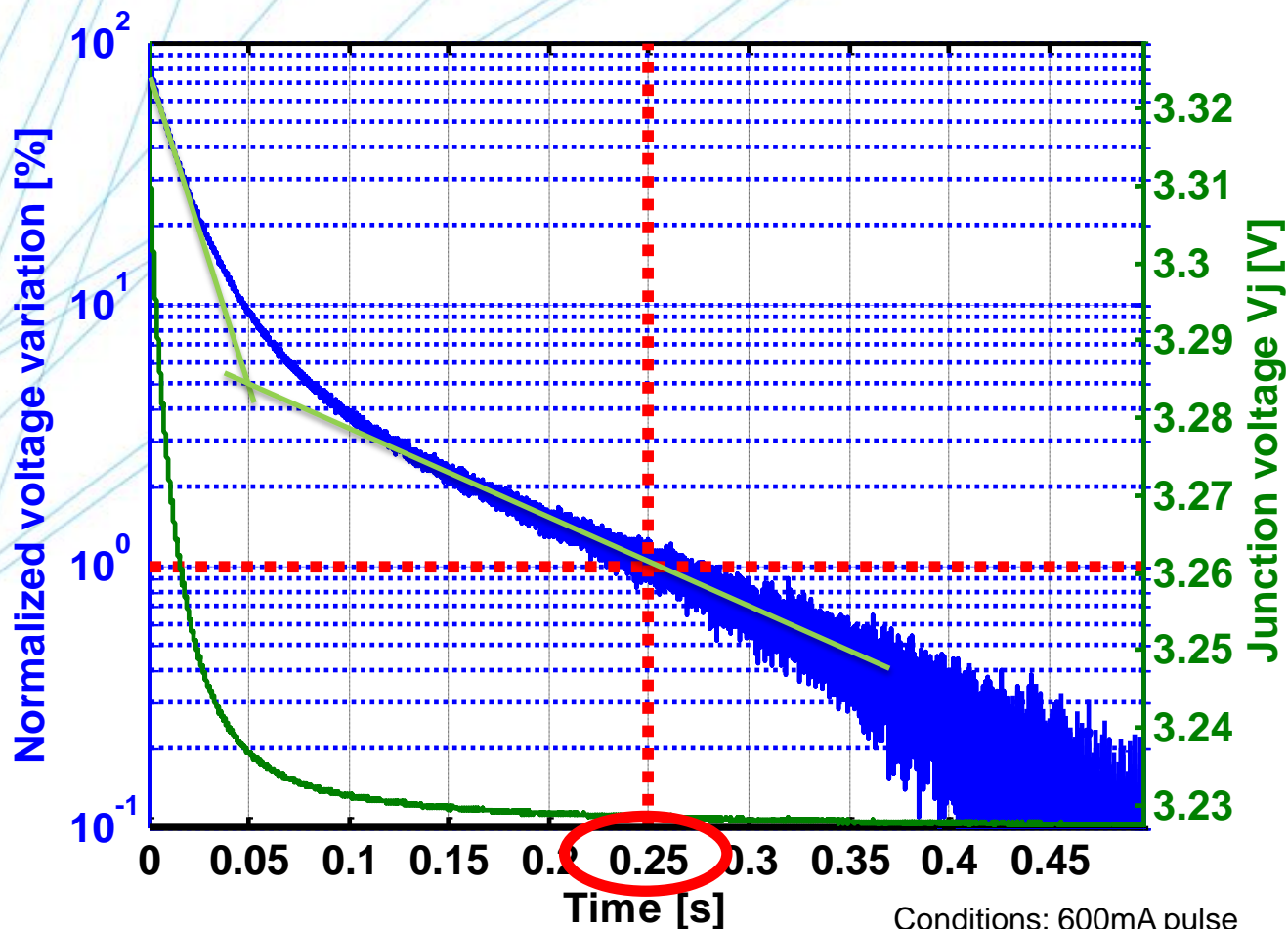
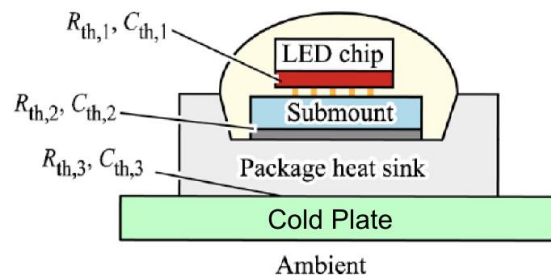


Thermal behavior of the junction

In our system, the junction temperature stabilizes within ¼ sec with respect to a reference heat sink

Stabilization time defined as time required to reach a voltage within 1% of the steady state value

The multiple time-constants behavior is justified by the multilayer thermal path between the junction and the heat sink.



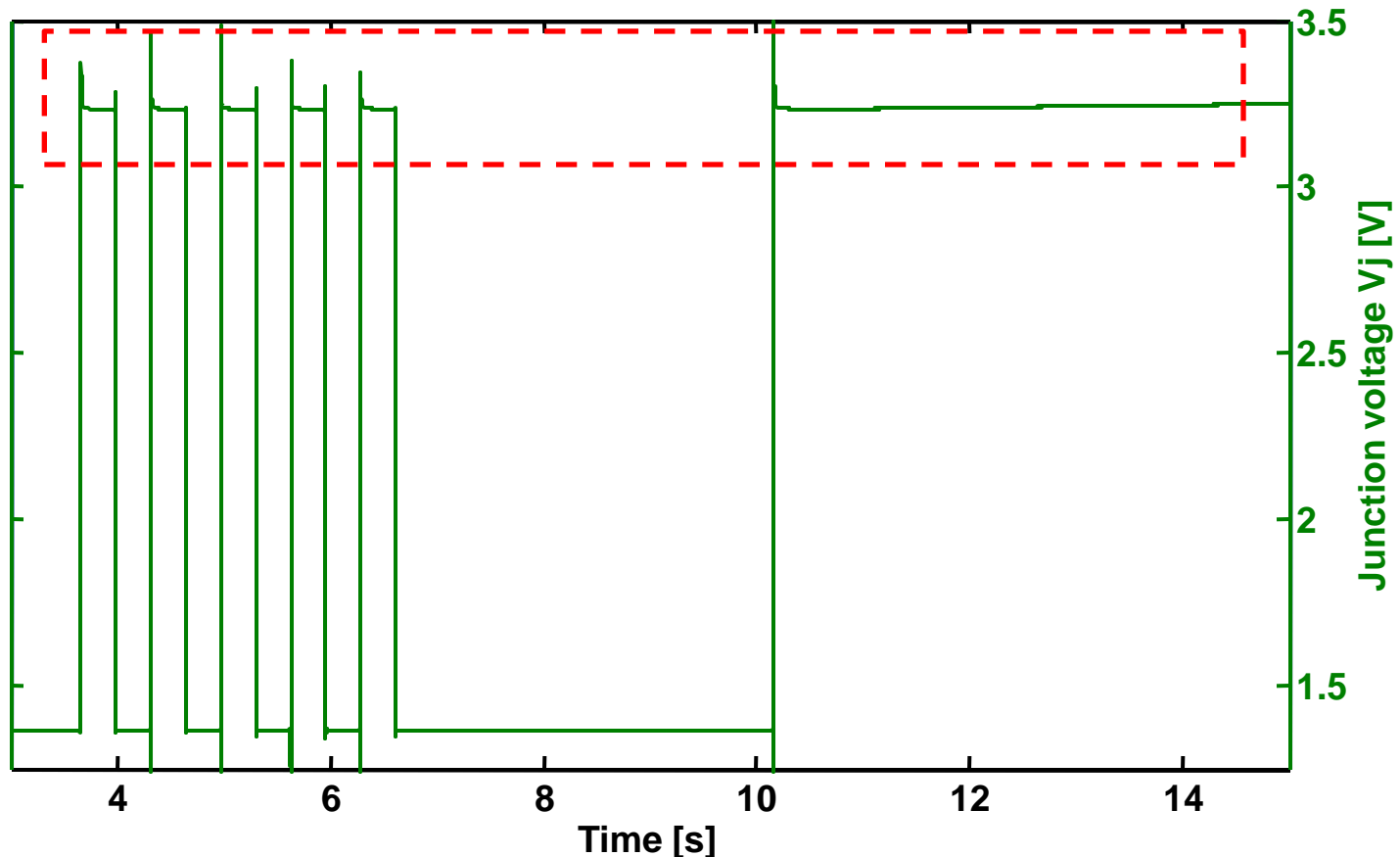
Conditions: 600mA pulse

Implementing the algorithm for setting T_j

Typically, the heat sink temp. feedback response time is much slower than the thermal stabilization time of the junction

- _ The heat sink thermal mass is much larger than the junction itself
- _ The junction has time to heat up considerably before the heat sink temp. feedback can react effectively

Conditions: target T_j at 45°C, current 600mA

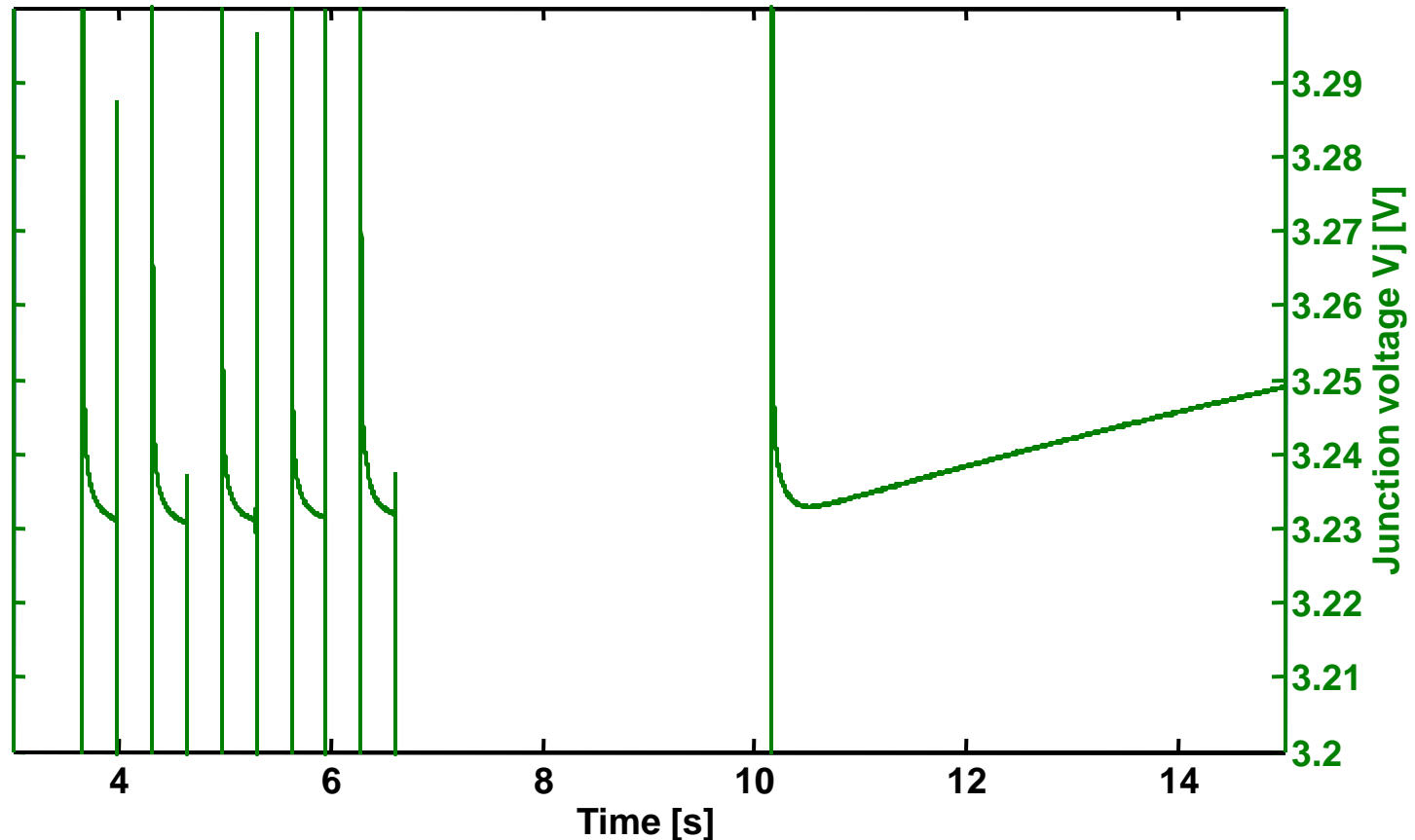


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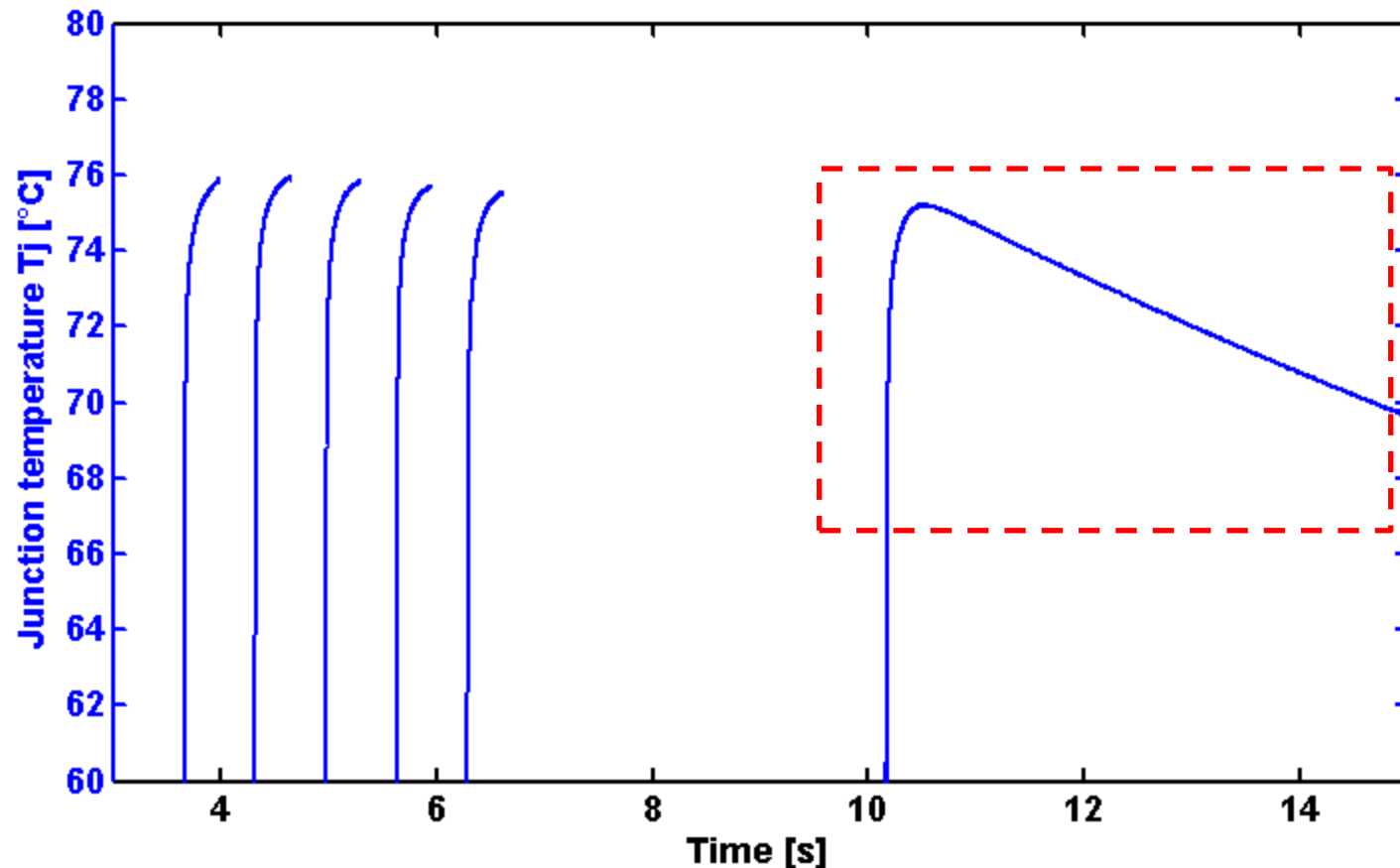


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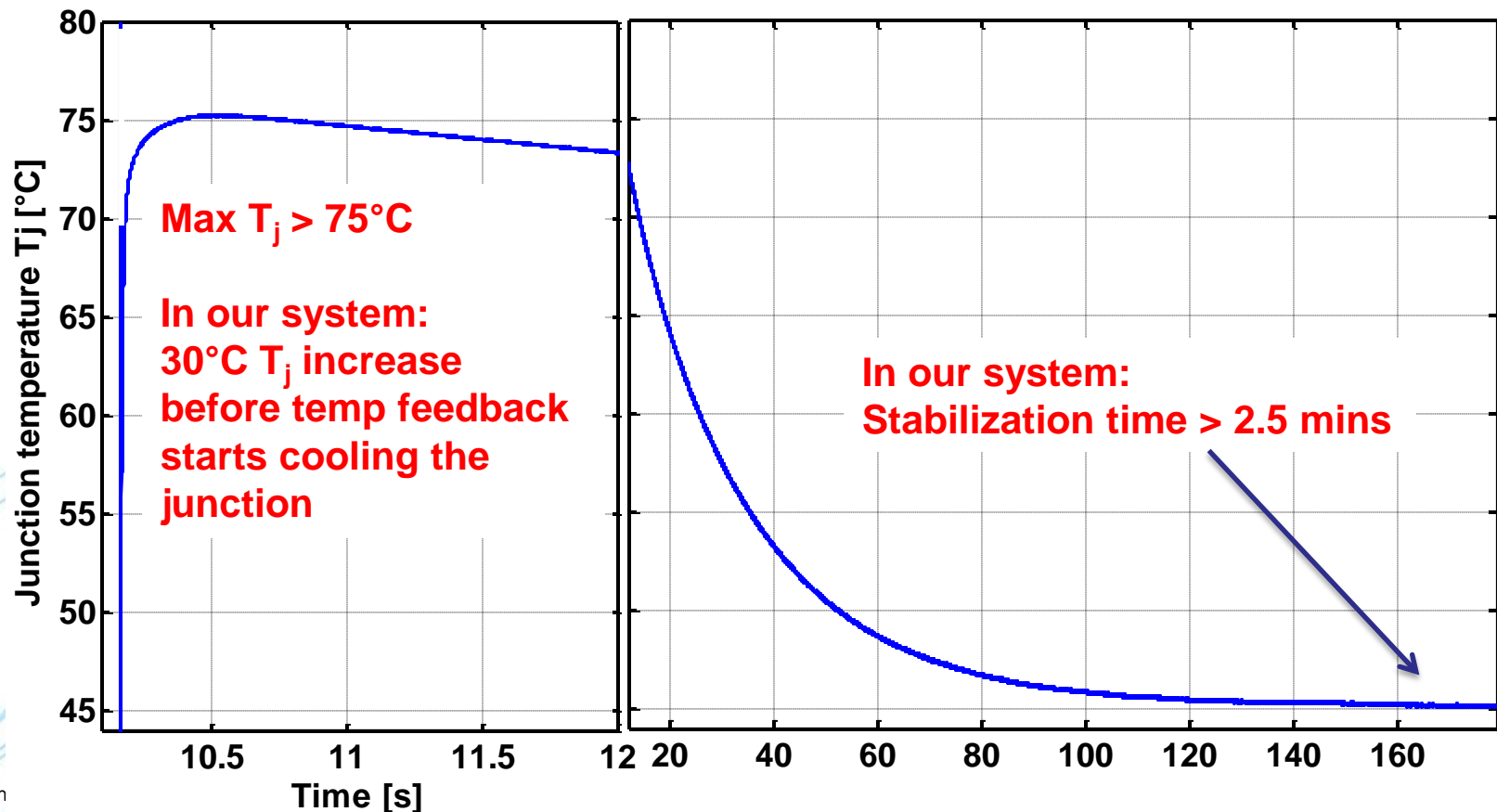


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Importance of avoiding T_j spikes during characterization

From SSL thermal simulation we can predict the steady state T_j for a given dissipated power

In order to properly predict SSL colorimetric/radiometric performance, the LED should be characterized at the expected T_j .

However, the characterization algorithm described before may cause the LED to temporarily overheat.

Junction overheating is known to be the source of LED degradation, reduced lifetime and possibly catastrophic failure.

If the LED is characterized near its maximum allowed T_j and at high current:

- Performance measurements are actually affected by degradation due to heat overstress
- Potential of catastrophic failure, mainly due to thermomechanical stress and associated failure mechanisms [Solid State Lighting Reliability: Components to Systems, van Driel, W.D.; Fan, X.J. (Eds.), ISBN 978-1-4614-3067-4]

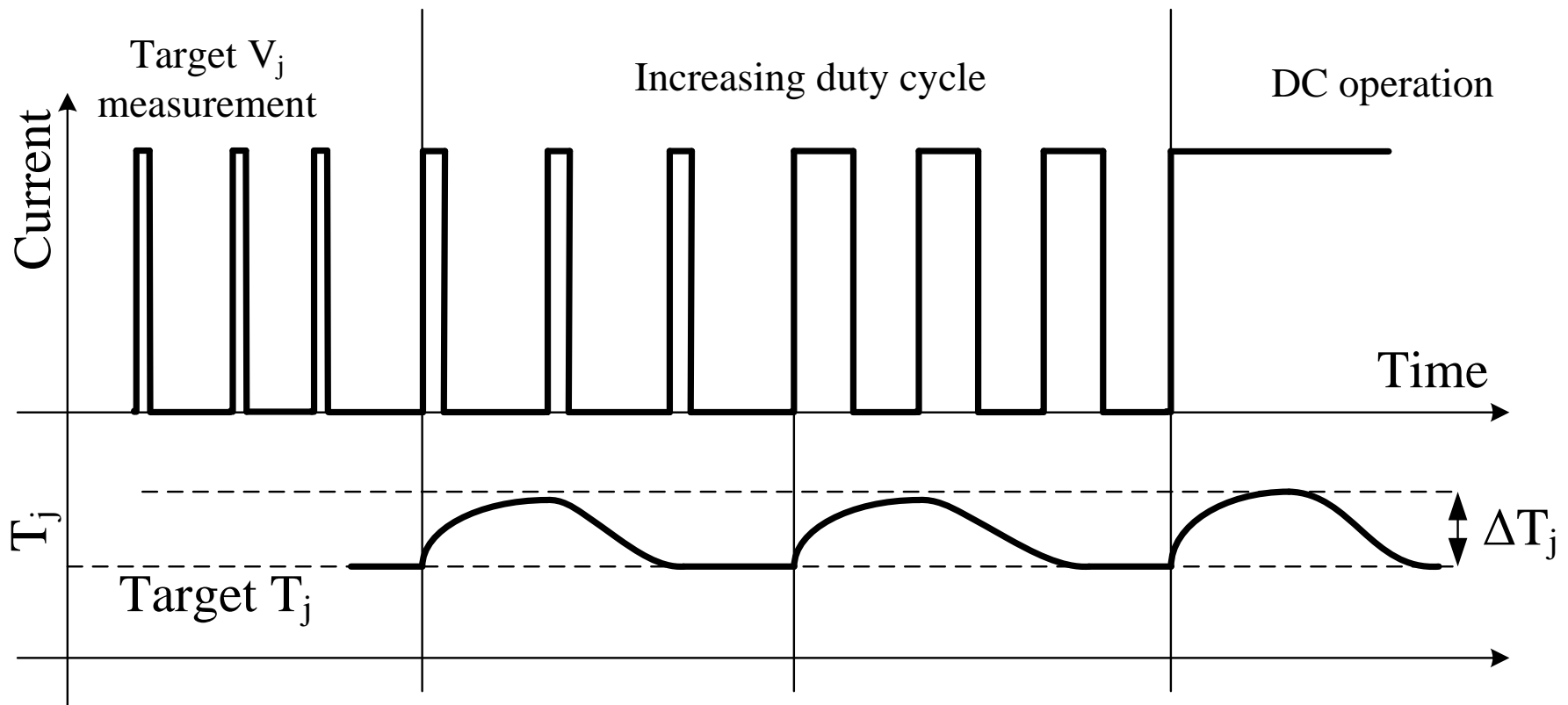
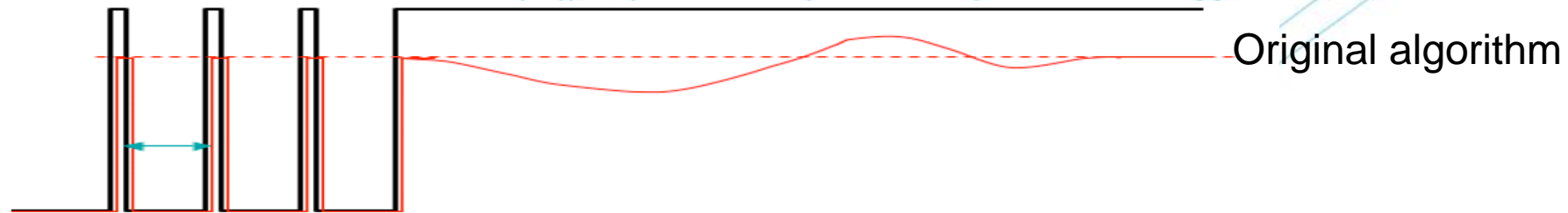
A new T_j stabilization algorithm

One can minimize the LED overheating by:

- _ Designing a very effective temperature control system. However, this solution has limitations since heat is generated directly within the junction and thermal mass of the heat sink is non negligible.
- _ Increasing gradually LED drive current from 0 to the desired value. This allows the temperature feedback system to maintain the T_j temperature over time even if increasing power is dissipated in the junction. However, this requires an analogic control over the current values, which may be unavailable.
- _ Alternatively, one can take advantage of the current pulsing capability that is already required to implement the original algorithm.

We propose a stabilization algorithm that gradually increases the duty cycle up to full DC operation. For every duty cycle step, the heat sink temperature is adjusted to maintain the T_j near its target value.

Proposed T_j stabilization algorithm

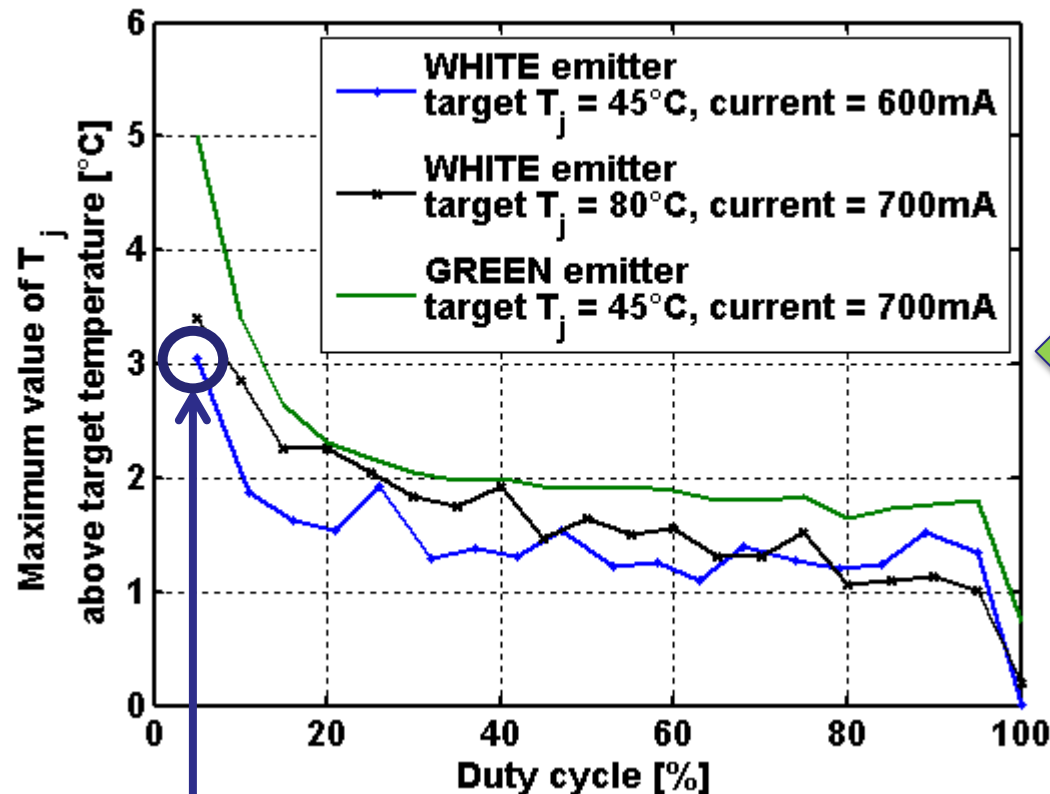


Experimental results



PerkinElmer ACULED

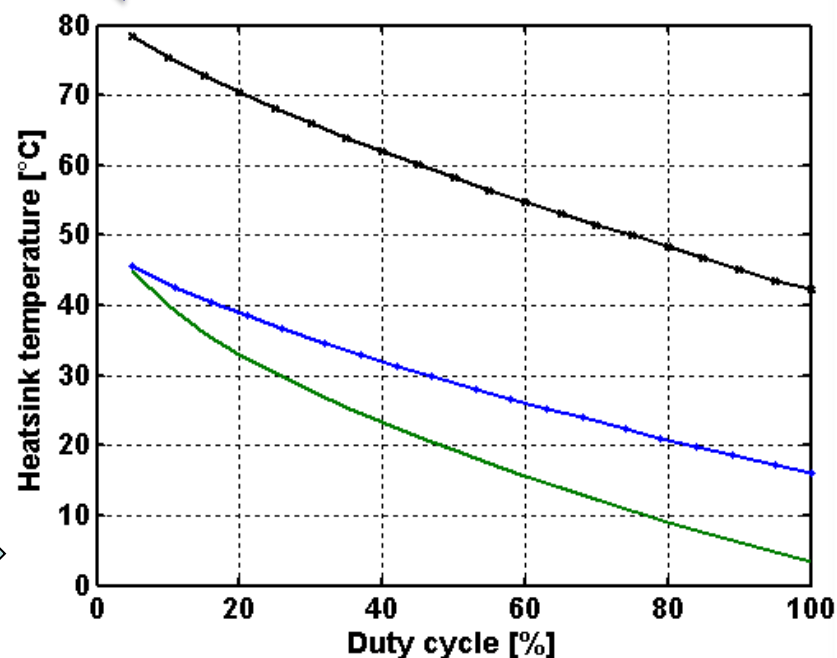
ACULED RGBW LED



With the original algorithm in these conditions, T_j increases by 30 $^{\circ}\text{C}$. Here the maximum T_j variation is +3 $^{\circ}\text{C}$

Heat sink temperature lowered with increasing duty cycle to maintain T_j near target temperature

Increase of T_j temperature is kept below 5 $^{\circ}\text{C}$ from the target value while Duty Cycle is increased from 5% to 100%



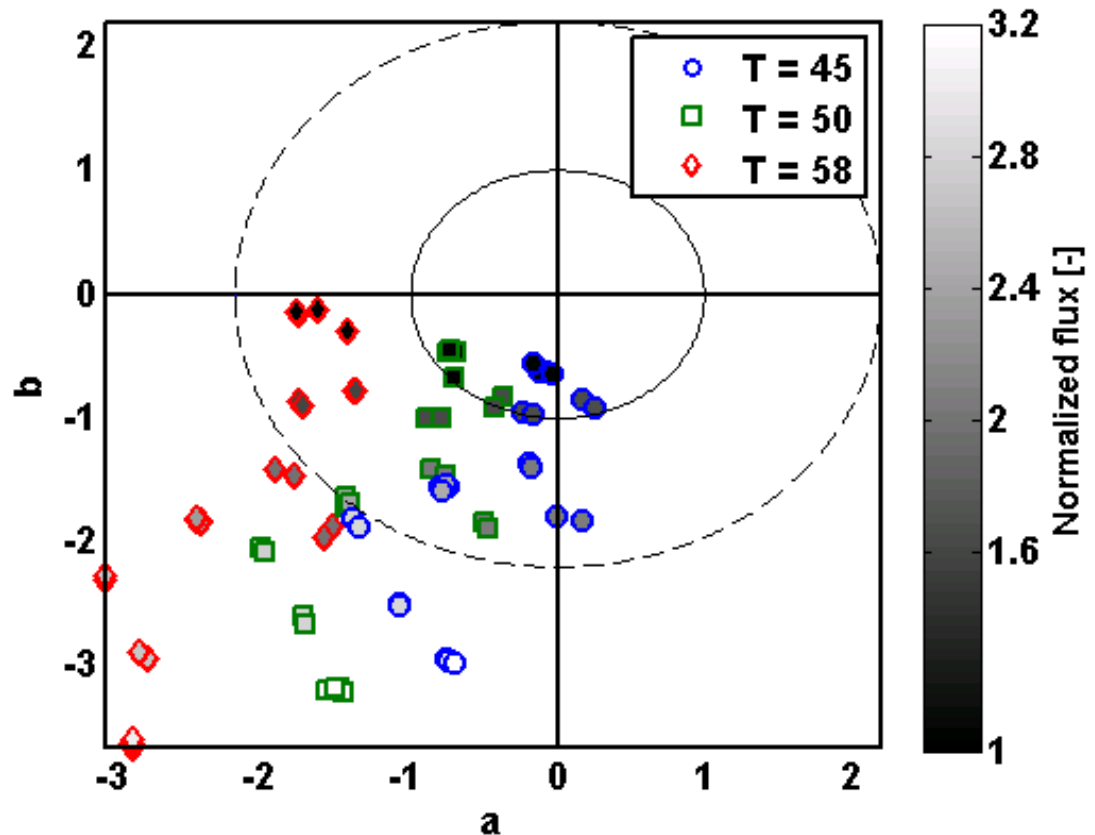
Color control feed forward algorithm based on accurate LED calibration

CIELab plot of color emitted from an ACULED RGBW LED using a feed-forward control algorithm that assumes constant LED junction temperature at $T_j=45^\circ\text{C}$, while ambient temperature vary from 45°C to 58°C .

The internal circle corresponds to CIE76 $\Delta E^*_{ab}=1$ (JND for sources [1])

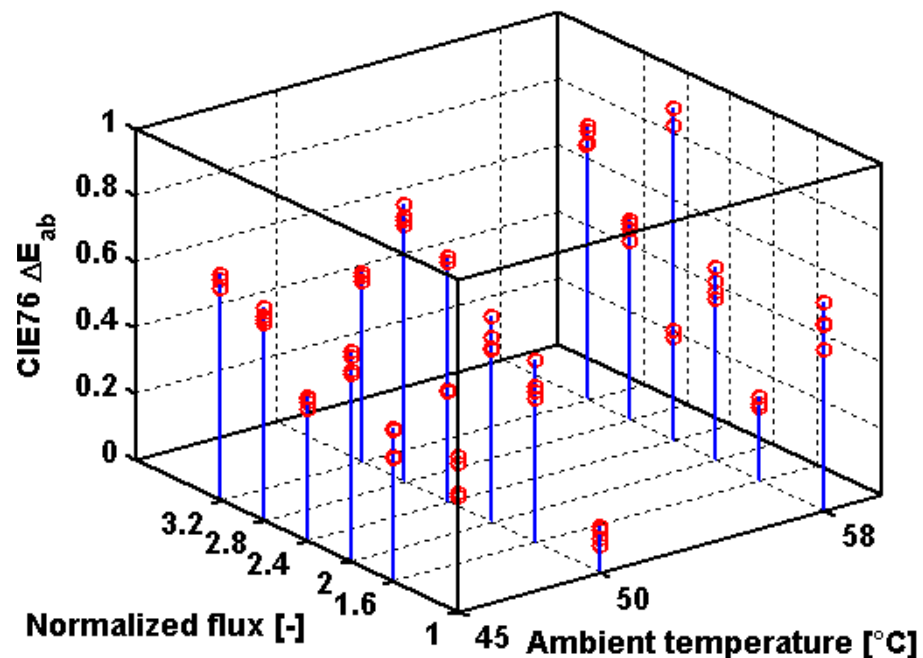
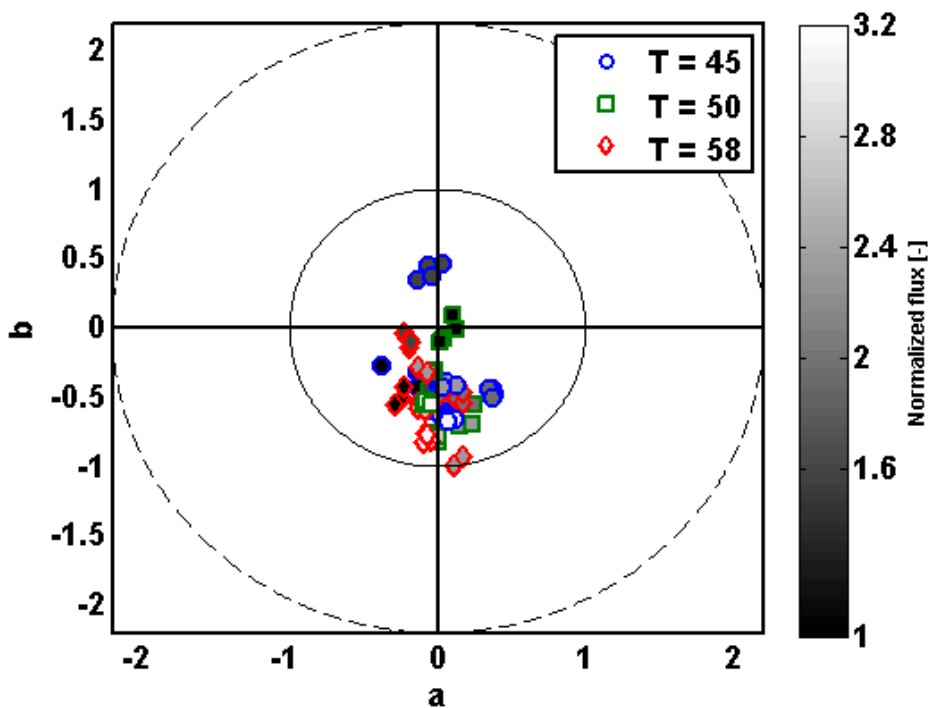
The external circle corresponds to CIE76 $\Delta E^*_{ab}=2.3$ (JND for surfaces [1])

The various color points correspond to 3 ambient temperature values and 6 values of flux from the LED. The flux vary by a factor 3.



Color control feed forward algorithm based on accurate LED calibration

The same plot, but using a control algorithm that takes into account real junction temperature. This algorithm is based on an appropriate LED characterization at multiple T_j temperatures. **The characterization near maximum operating T_j was only possible with the proposed temperature stabilization algorithm.** Otherwise, we experienced several LED failures!



Good temperature characterisation of LEDs is mandatory for SSL design using high brightness LEDs when optical performance has to be controlled

A junction temperature setting algorithm is proposed to allow reliable LED characterisations at high temperatures and currents

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